

E2

0.10

0.05

CAB

C NOTE 3

24X **b** 

Ф

**DATE 17 APR 2012** 

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION b APPLIES TO PLATED TERMINAL
  AND IS MEASURED BETWEEN 0.15 AND 0.30 MM
  FROM TERMINAL TIP.
  COPLANARITY APPLIES TO THE EXPOSED PAD
  AS WELL AS THE TERMINALS.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.70	0.80	
A1	0.00	0.05	
А3	0.20 REF		
b	0.20	0.30	
D	4.00 BSC		
D2	2.00	2.20	
E	4.00 BSC		
E2	2.00	2.20	
е	0.50 BSC		
K	0.20		
L	0.30	0.50	
L1	0.00	0.15	

## **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code

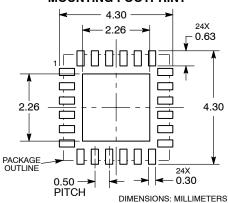
= Assembly Location

= Wafer Lot L = Year W = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G", may or not be present.

## **MOUNTING FOOTPRINT**



DOCUMENT NUMBER:	98AON48315E	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	WQFN24 4X4, 0.5P		PAGE 1 OF 1

ON Semiconductor and (III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

е

**BOTTOM VIEW** 

e/2